

<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/630,124	HAUB ET AL.
	Examiner Pablo N. Tran	Art Unit 2618

SEARCHED			
Class	Subclass	Date	Examiner
488	67.11	03/31/07	+2
	118.1		
	296.1 - 296.4		
	67.13		
	296		
	232.1		
	298		
	280.1		
	102		
	104		
	123		
	252.1		
	234.1 - 234.2		
380	278	↓	↓

<b>Search Notes (continued)</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/630,124	HAUB ET AL.
Examiner	Art Unit	
Pablo N. Tran	2618	

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>